

N-Channel 200 V (D-S) MOSFET

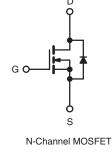
PRODUCT SUMMARY					
V _{DS} (V)	200				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2			
Q _g (Max.) (nC)	8.2				
Q _{gs} (nC)	1.8				
Q _{gd} (nC)	4.5				
Configuration	Single				

FEATURES

- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- Fast switching
- Ease of paralleling
- Simple drive requirements







ABSOLUTE MAXIMUM RATINGS (TC	= 25 °C, un	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	200	v	
Gate-Source Voltage			V _{GS}	± 20	v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	- I _D	1.0		
Continuous Drain Current	VGS at 10 V	T _C = 100 °C		0.8	А	
Pulsed Drain Current ^a			I _{DM}	5.0		
Linear Derating Factor				0.025	W/°C	
Linear Derating Factor (PCB Mount) ^e				0.017	vv/ C	
Single Pulse Avalanche Energy ^b			E _{AS}	50	mJ	
Repetitive Avalanche Current ^a			I _{AR}	0.96	А	
Repetitive Avalanche Energy ^a			E _{AR}	0.31	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D 3.1 2.0		w	
Maximum Power Dissipation (PCB Mount) ^e	T _A = 25 °C					
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak Temperature) d	for	10 s		300		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 81 mH, $R_G = 25 \Omega$, $I_{AS} = 0.96 \text{ A}$ (see fig. 12). c. $I_{SD} \le 3.3 \text{ A}$, dl/dt $\le 70 \text{ A/µs}$, $V_{DD} \le V_{DS}$, $T_J \le 150 \text{ °C}$.

d. 1.6 mm from case.

e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	40	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	60	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.30	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	: V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	-	: 200 V, V _{GS} = 0 V 7, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.58 A ^b	-	1.2	-	Ω
Forward Transconductance	g _{fs}	V _{DS} =	$V_{DS} = 50 \text{ V}, \text{ I}_{D} = 0.58 \text{ A}$		-	-	S
Dynamic		<u>.</u>					
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	140	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		53	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1			15	-	
Total Gate Charge	Qg			-	-	8.2	
Gate-Source Charge	Q_gs	$V_{GS} = 10 V$	I _D = 3.3 A, V _{DS} = 160 V, see fig. 6 and 13 ^b	-	-	1.8	nC
Gate-Drain Charge	Q _{gd}		oco ng. o ana ro	-	-	4.5	
Turn-On Delay Time	t _{d(on)}			-	8.2	-	
Rise Time	t _r	V _{DD} =	V _{DD} = 100 V, I _D = 3.3 A,		17	-	ns
Turn-Off Delay Time	t _{d(off)}	$R_g = 24 \Omega$, $R_D = 30 \Omega$, see fig. 10 ^b		-	14	-	
Fall Time	t _f			-	8.9	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	nH
Internal Source Inductance	L _S			-	6.0	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	0.96	А
Pulsed Diode Forward Current ^a	I _{SM}			-	-	7.7	
Body Diode Voltage	V_{SD}	T _J = 25 °C,	$I_{\rm S}$ = 0.96 A, $V_{\rm GS}$ = 0 V ^b	-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 °C 1	- 2 2 A dl/dt, 100 A/v= h	-	150	310	ns
Body Diode Reverse Recovery Charge	Q _{rr}	- T _J = 25 °C, I _F = 3.3 A, dI/dt = 100 A/µs ^b		-	0.60	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by			y Ls and	L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

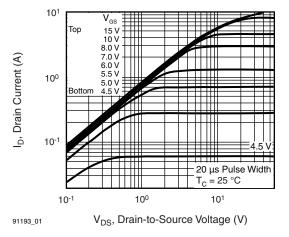


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

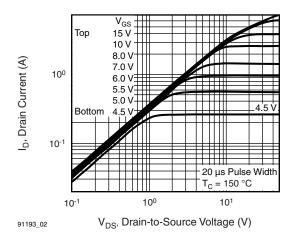


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

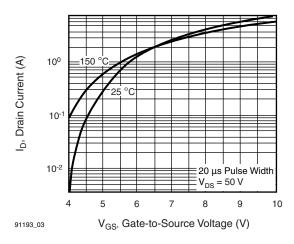


Fig. 3 - Typical Transfer Characteristics

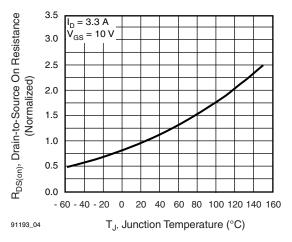


Fig. 4 - Normalized On-Resistance vs. Temperature

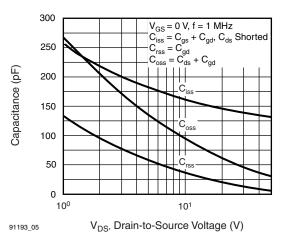


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

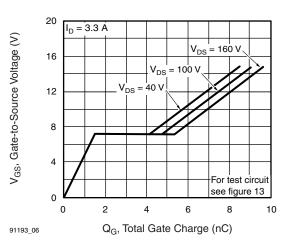


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

FQT4N20LTF



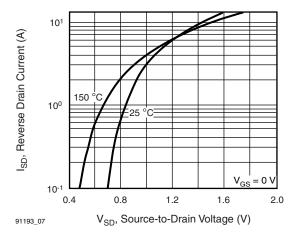


Fig. 7 - Typical Source-Drain Diode Forward Voltage

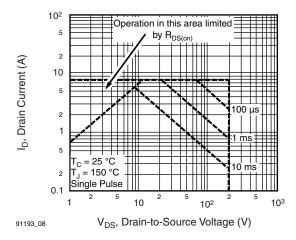


Fig. 8 - Maximum Safe Operating Area

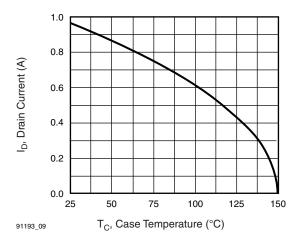


Fig. 9 - Maximum Drain Current vs. Case Temperature

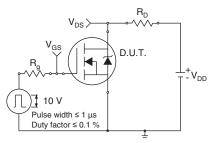


Fig. 10a - Switching Time Test Circuit

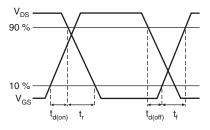
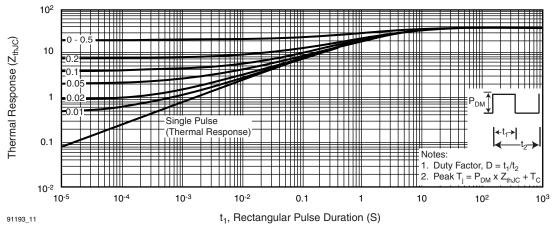


Fig. 10b - Switching Time Waveforms







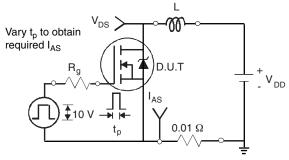


Fig. 12a - Unclamped Inductive Test Circuit

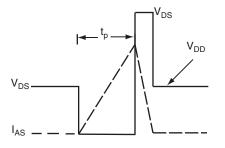


Fig. 12b - Unclamped Inductive Waveforms

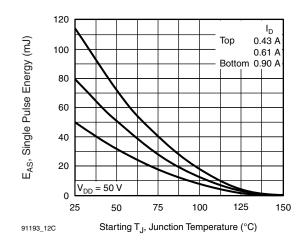


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

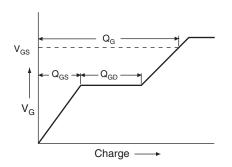


Fig. 13a - Basic Gate Charge Waveform

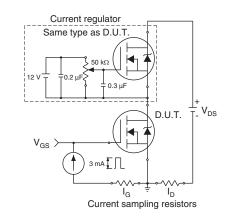
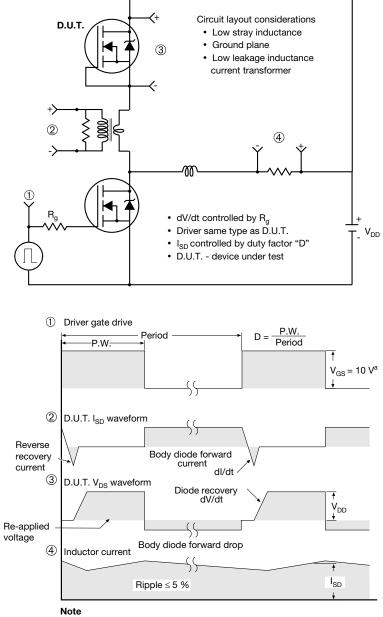


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



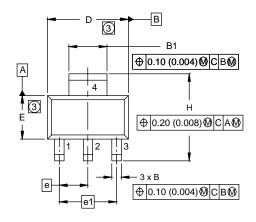
a. V_{GS} = 5 V for logic level devices

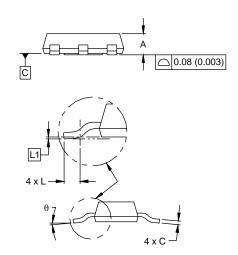
Fig. 14 - For N-Channel

FQT4N20LTF



SOT-223





	MILLI	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.0024 BSC		
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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